



Using Advanced Manufacturing Techniques for Thermal Management of High-Reliability Power Components

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IMPORTANT DISCLAIMER

- The numbers in the presentation are not fully accurate due to confidentiality agreements, but represent the results of studies done for designs of high reliability modules
- The presentation is intended as a showcase how to achieve high reliability. As each module is unique, each design requires its own technical approaches
- Special thank you to Dr. Fang Luo, Riya Paul, Hongwu Peng and Amol Deshpande from University of Arkansas for providing a technical portion of the subsequent presentation
- Thank you to Heraeus for approving the use of proprietary graphs and information in this presentation

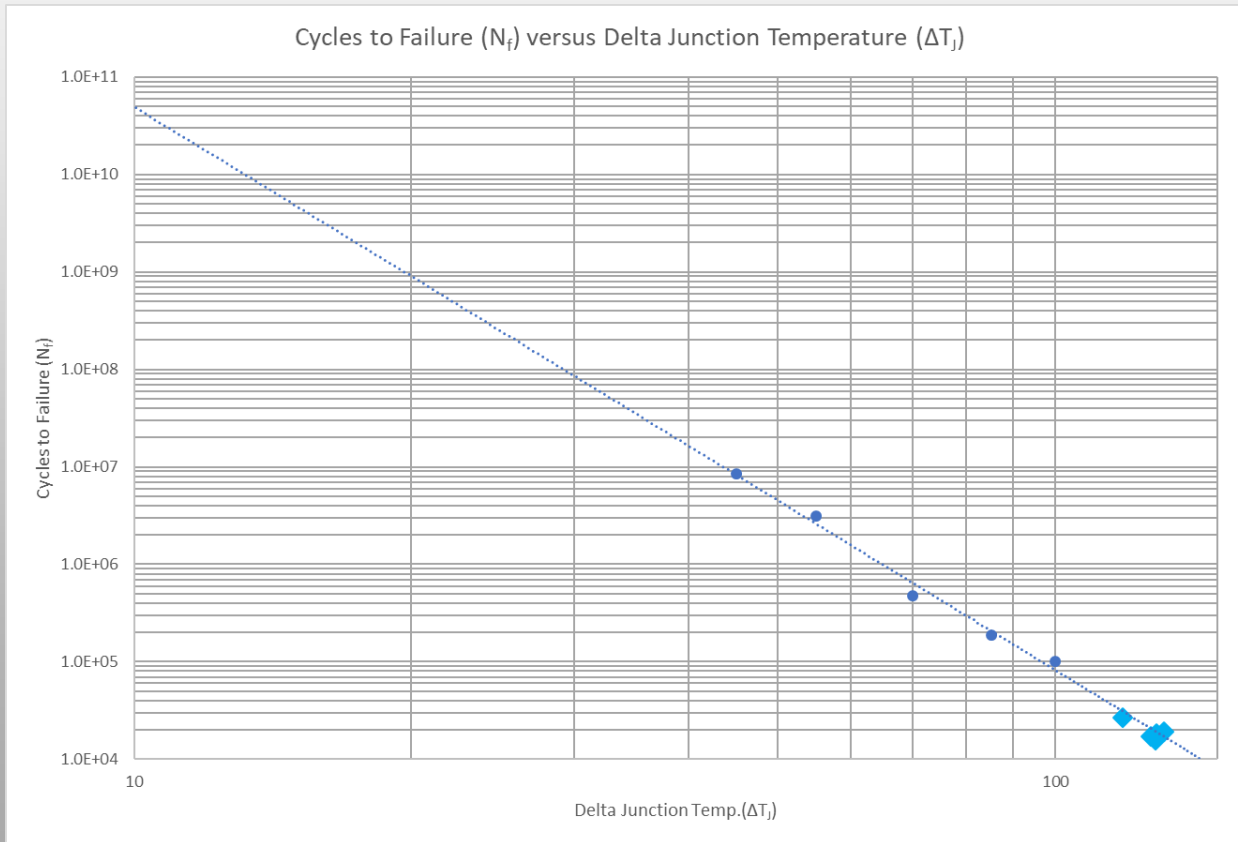


Why is Thermal Management Important?

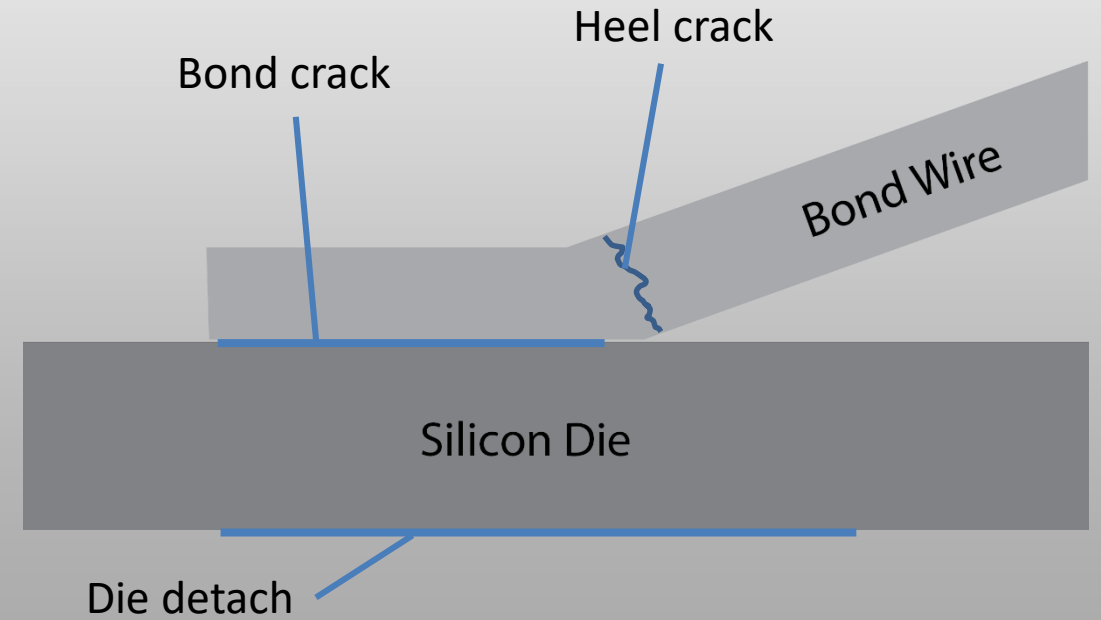
- SiC devices can withstand temperatures beyond 200°C. Why do I need to worry about thermal management then?
- High reliability = operation with very low failure rate
- Most failures are not due to the temperature itself, but due to thermal stress caused by cyclical change in temperature

Typical Failure Mechanisms for Temperature Changes

- Typical lifetime graph (Al Wire Bond)



- Most common failures mode: interconnect failures

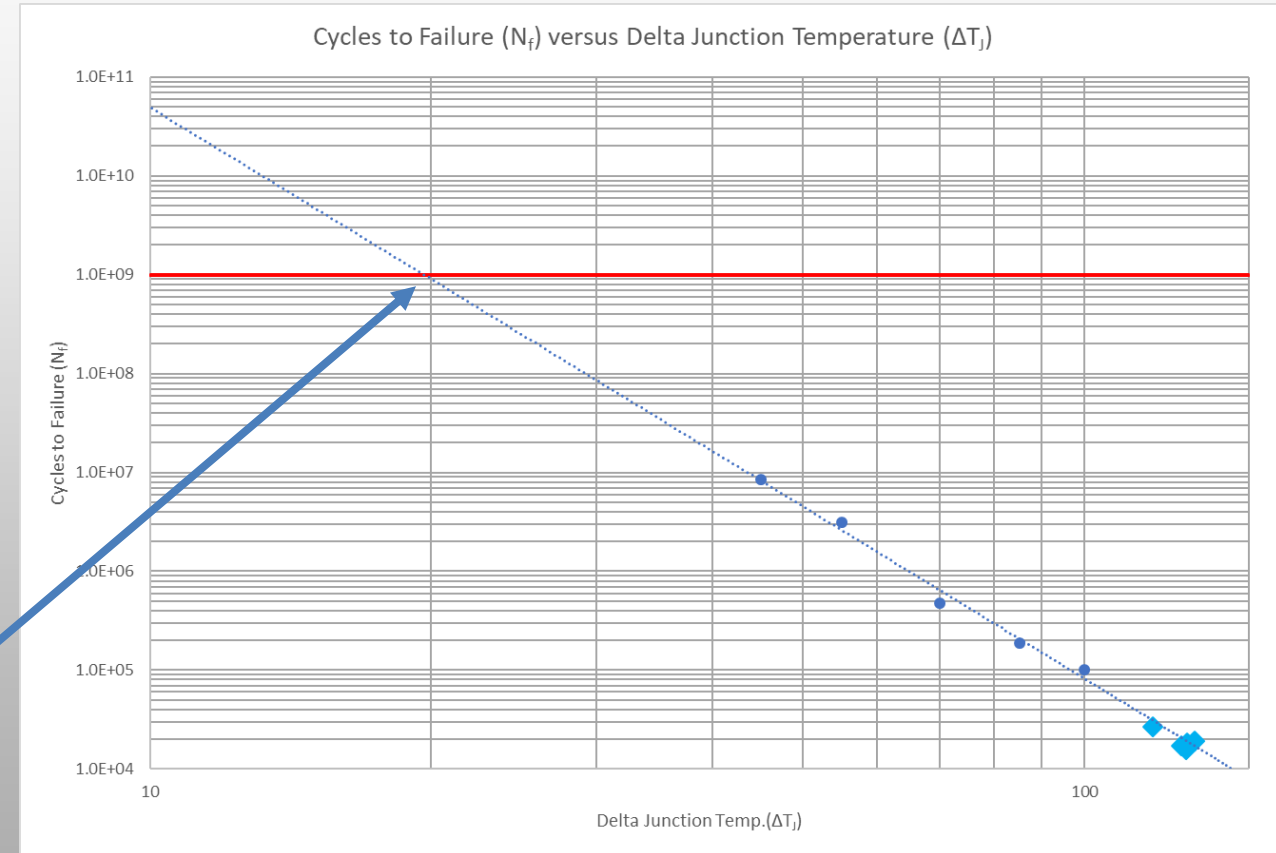


Case Study: Robotic Manufacturing

- Robotic precision positioning system
 - 24/7 operation
 - 20 ms positioning pulse @ 100 Hz
 - 300 V DC, 40 A_{PEAK}
 - 8 Hz operation
 - 4 year expected life

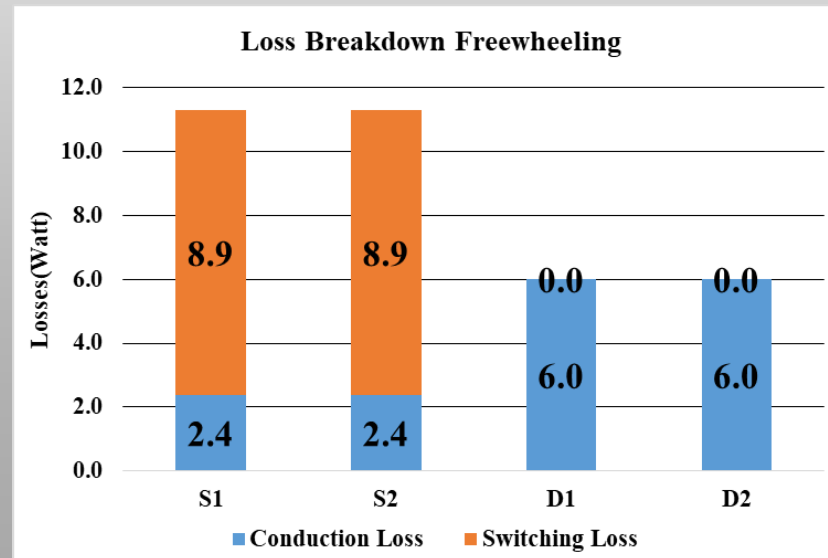
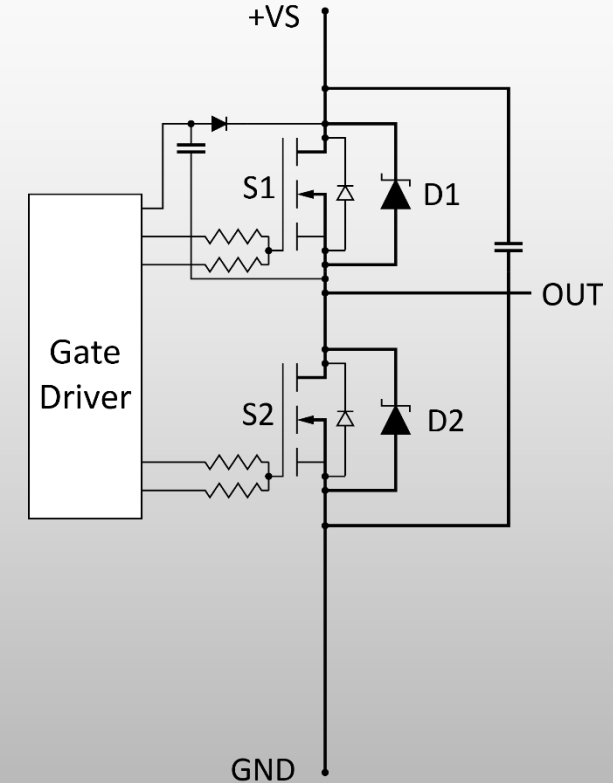
→ 1 billion power cycles over lifetime

- Junction temperature rise per power cycle must be less than 20 K when using Al wire bond



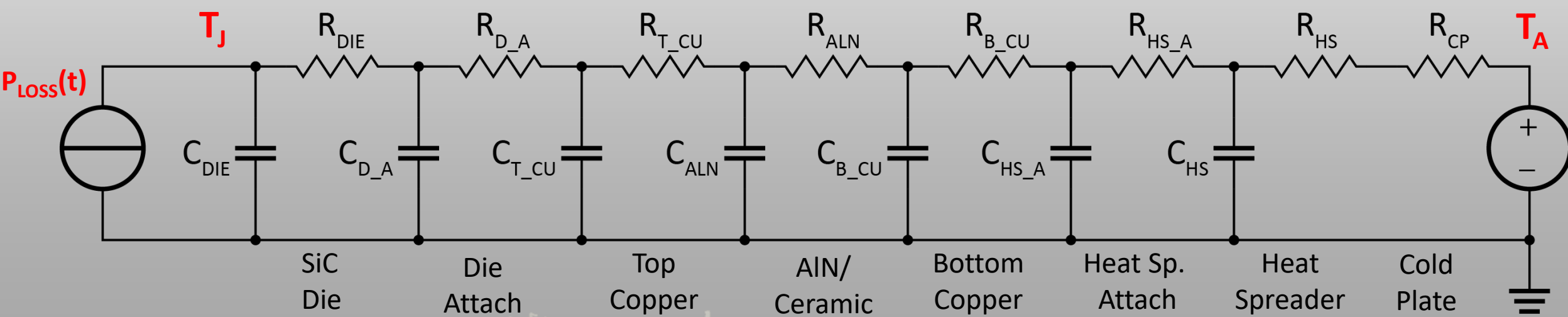
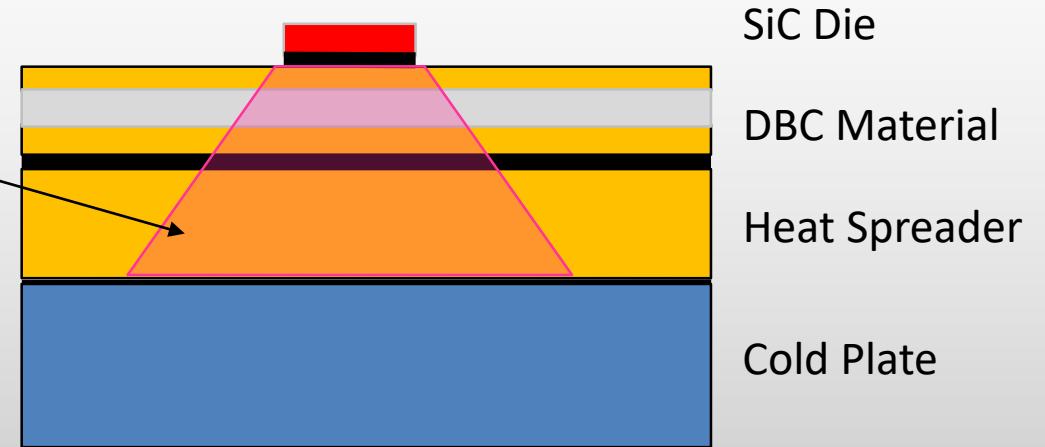
Power Loss Contributors (PWM Control)

- Conduction Loss: $P = \int I^2(t) \cdot R_{DS(on)} dt$
- Switching losses (unless zero current switching is suitable)
 - Switching losses also depend on gate drive resistance
- Case study example
 - $P_{LOSS} = 34.6 W$



Thermal Impact of Power Loss – Simulation Model

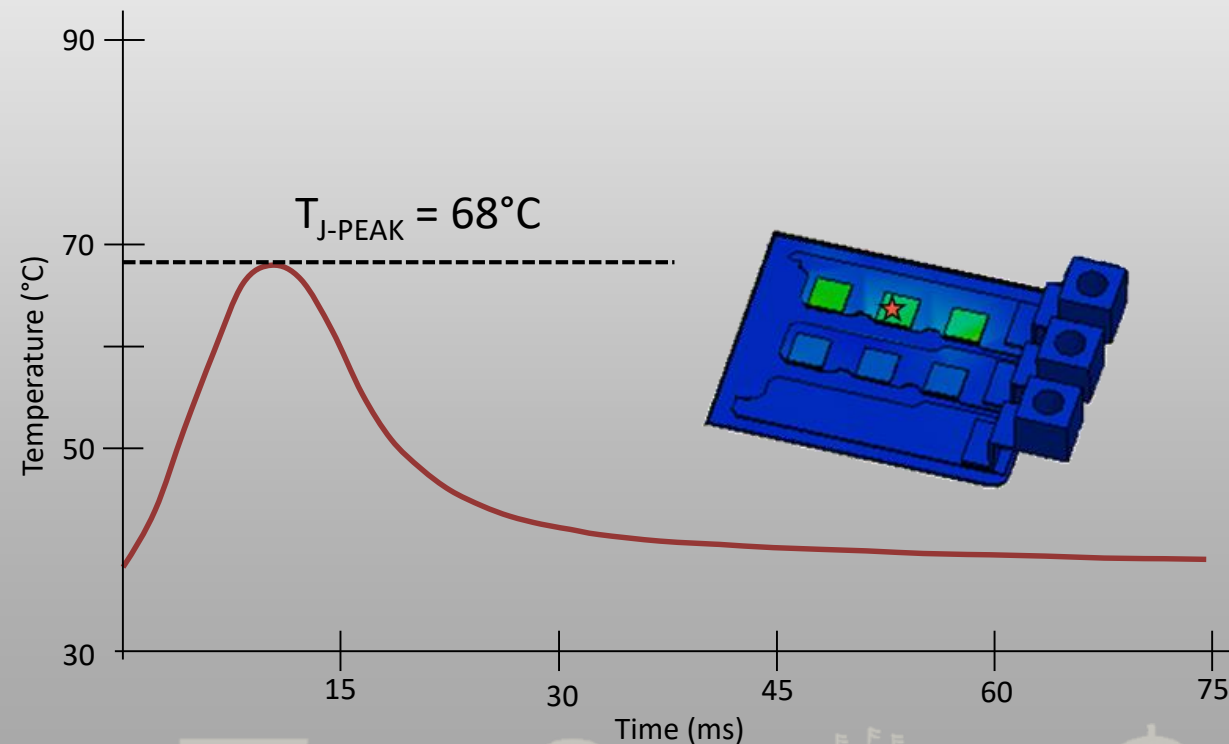
- DBC stack-up
 - Heat dissipation angle assumed to be 45°
- Resulting thermal model
 - Cauer R-C Thermal Network (w/o cold plate attach)



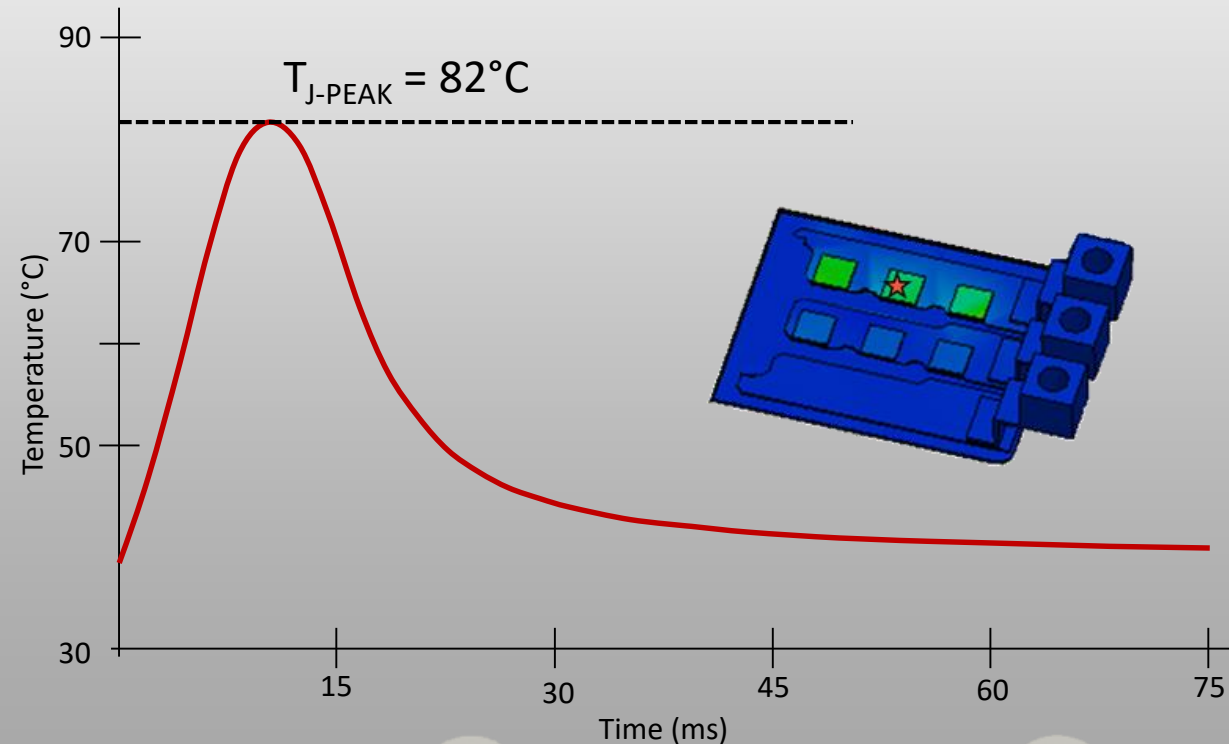
Simulation of the Thermal Impact due to Power Loss

- Simulation with industry standard DBC stack-up:
 - 0.3mm (Cu) + 0.5mm (AlN) + 0.3mm (Cu)

$R_G=0 \Omega$: $\Delta T_J=31 \text{ K}$

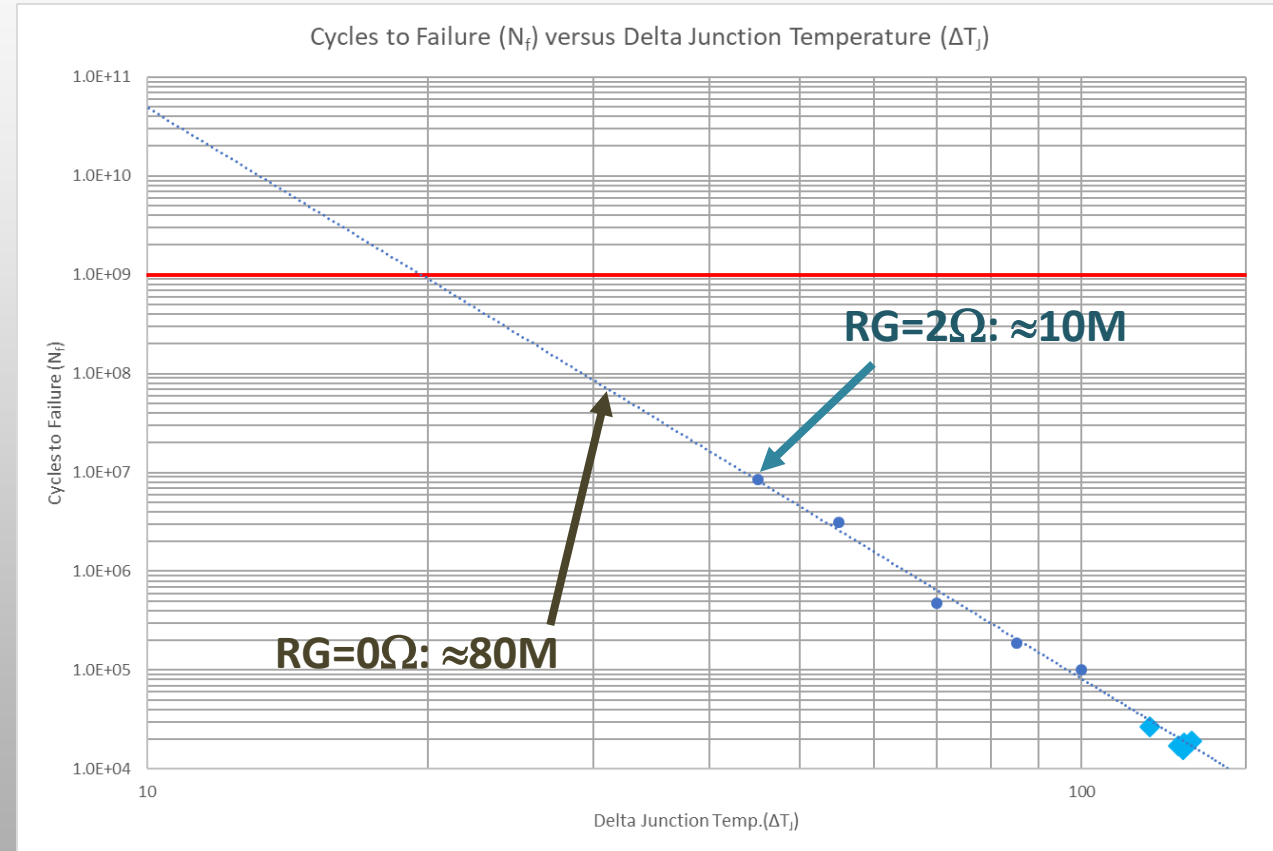


$R_G=2 \Omega$: $\Delta T_J=45 \text{ K}$



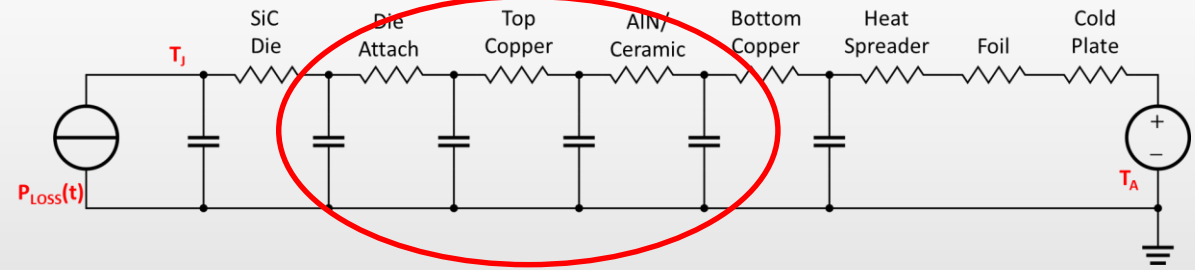
Reliability Challenge

- The system generates 34.6 W pulses of power loss in the Silicon Carbide MOSFET
- To achieve 1 billion power cycles, we need to keep the temperature rise of the MOSFETs below 20 K if we use common mounting techniques
- Thermal simulations show that the conditions are not met, resulting in lower reliability of the module

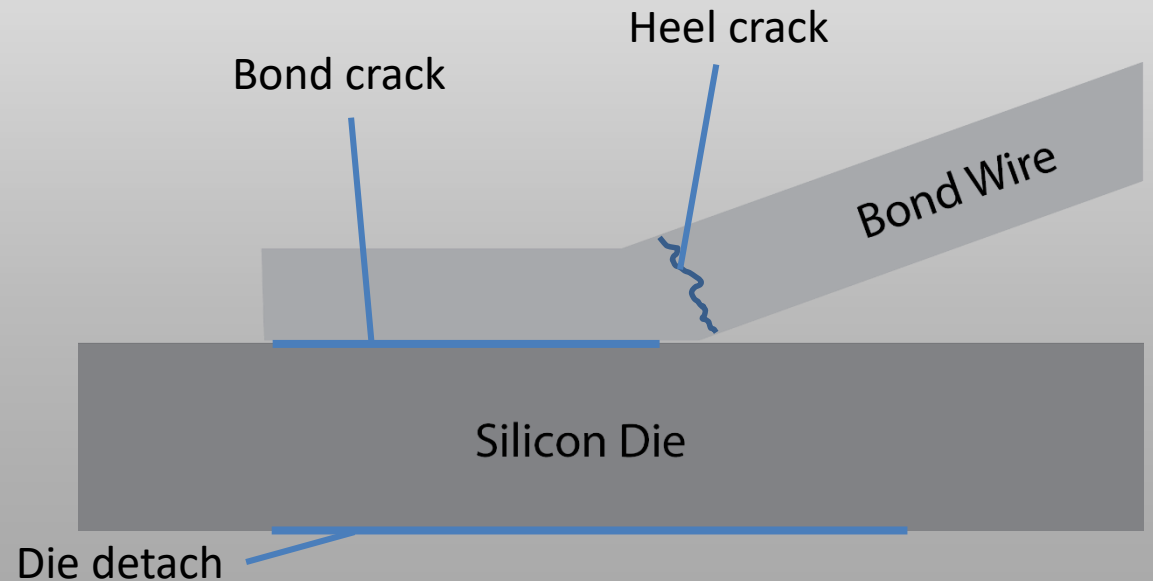


- Option 1: Increase the thermal capacitance close to the die attach to reduce the temperature rise
 - Example: add graphite layer
- Option 2: reduce temperature increase by adding more output MOSFETs in parallel
 - Impact on cost of module
- Option 3: Relax temperature rise requirements by selecting alternative mounting techniques
 - Replace the traditional aluminum wire bonding with alternative connectivity methods

Ways to Improve the Reliability



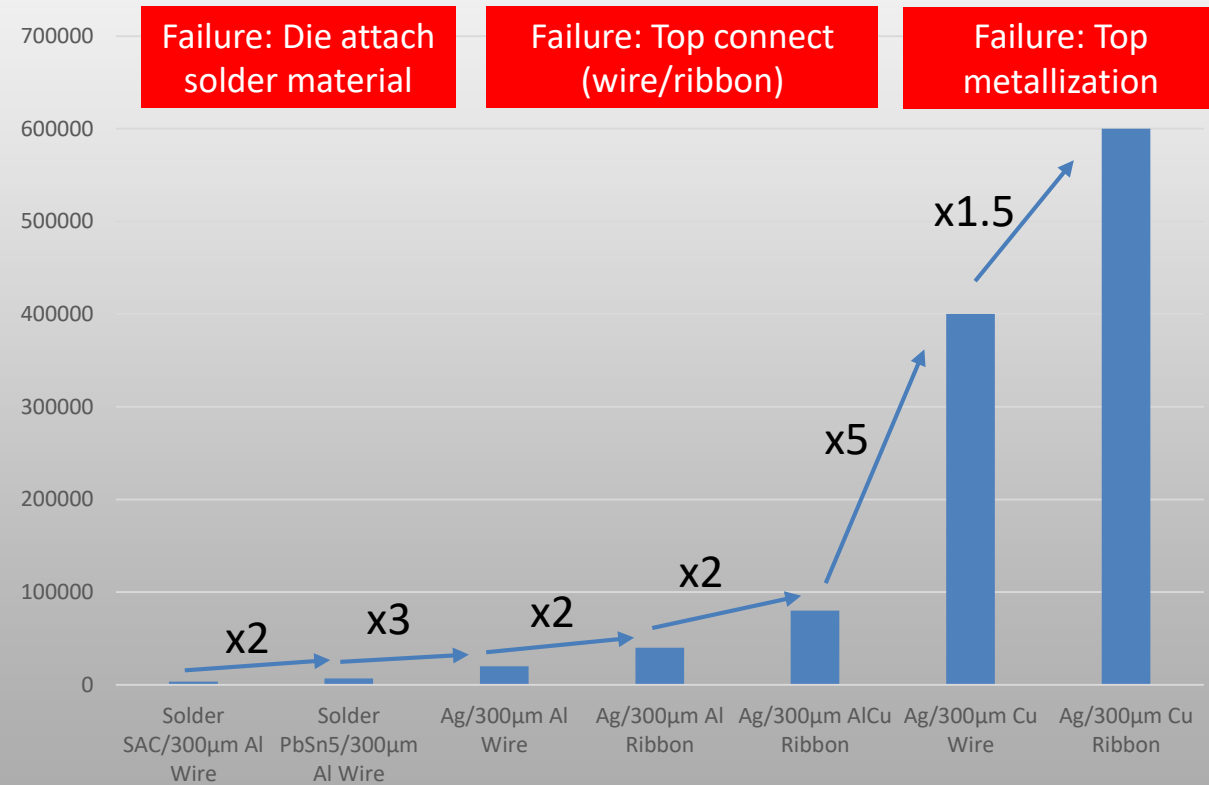
Tweakable thermal capacitances



Considering Package Material and Technology

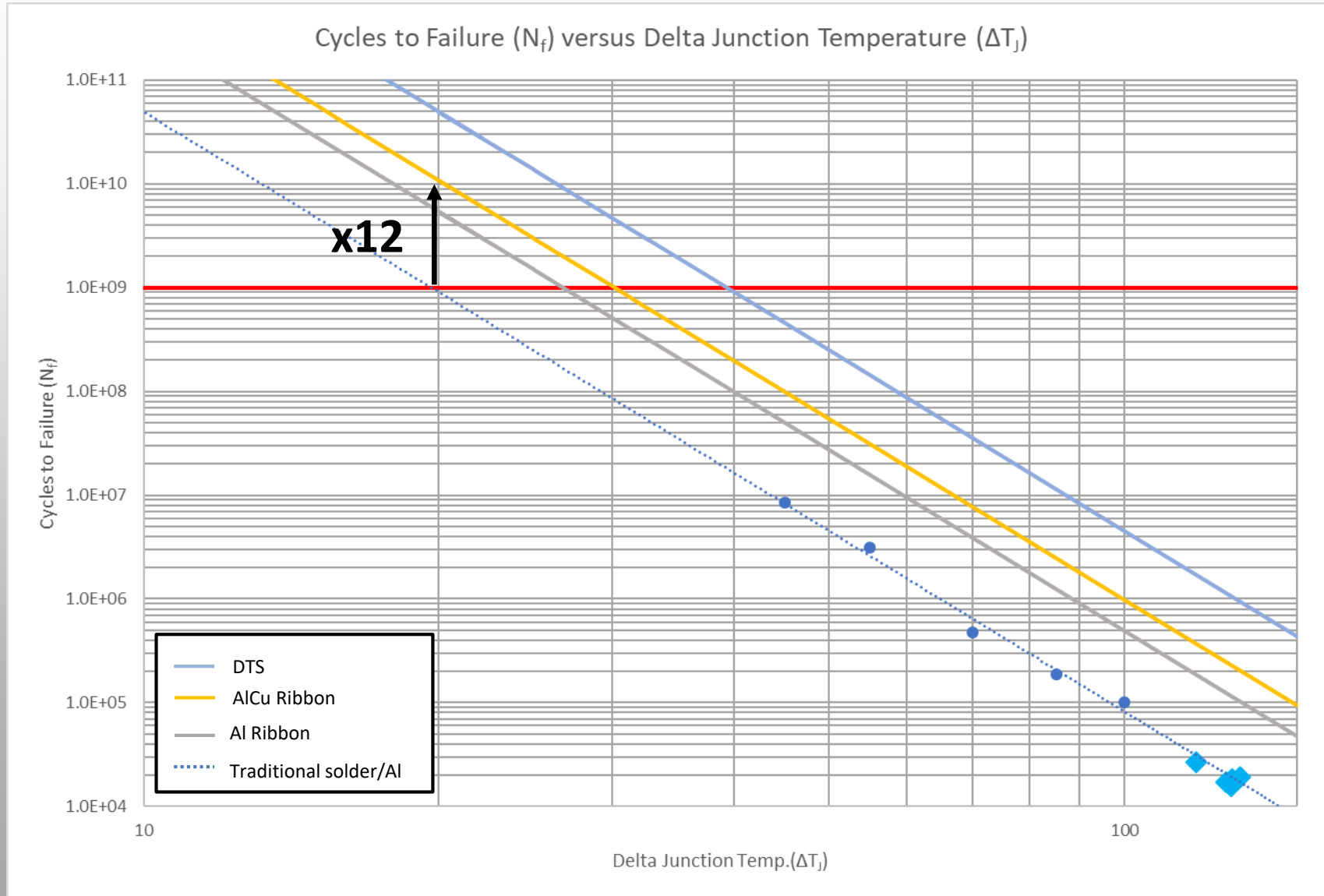
- The graph provided by Heraeus shows the relative improvement from traditional solder and Al wire bond technology to advanced interconnect options
- Moving from Al wire/solder to AlCu ribbon/silver improves reliability by a factor of 12

Thermal Cycles for $\Delta T=150K$ ($T_M=105^\circ C$)



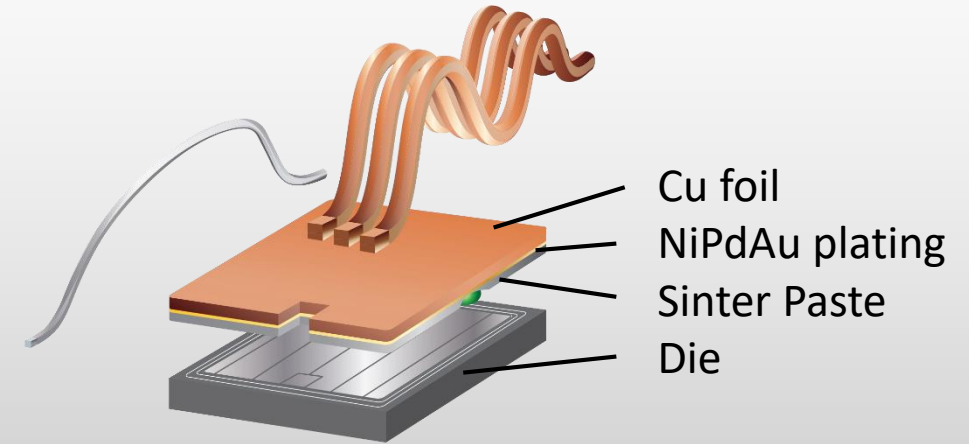
Source: Heraeus

Reliability Prediction for Interconnect Options



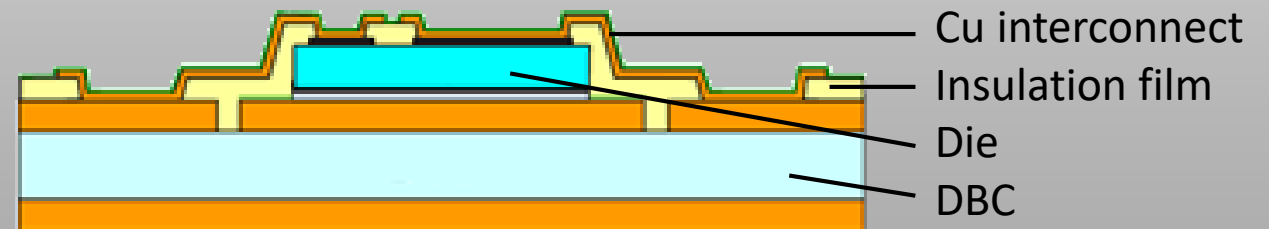
Outlook: Further Reliability Improvements

- DTS (Die-Top System)
 - Heraeus indicates an increased power cycling capability by a factor of 50 compared to soldered die with Al wire interconnection
 - Comparison done on substrate level, i.e. DBC with attached die



Source: Heraeus

- Wire-less interconnections
 - Adds new path for power dissipation
 - Shorter connections



- Long-term reliability of power modules depend strongly on the temperature rises when operating the module. Thermal management is critical for designing modules that meet defined reliability requirements
- Thermal management is not only about removing the heat from the module, but also providing thermal capacitances within the module design to smoothen out short-term spikes
- Modern mounting techniques reduce the burden on thermal management, but they don't eliminate the need for thorough analysis



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